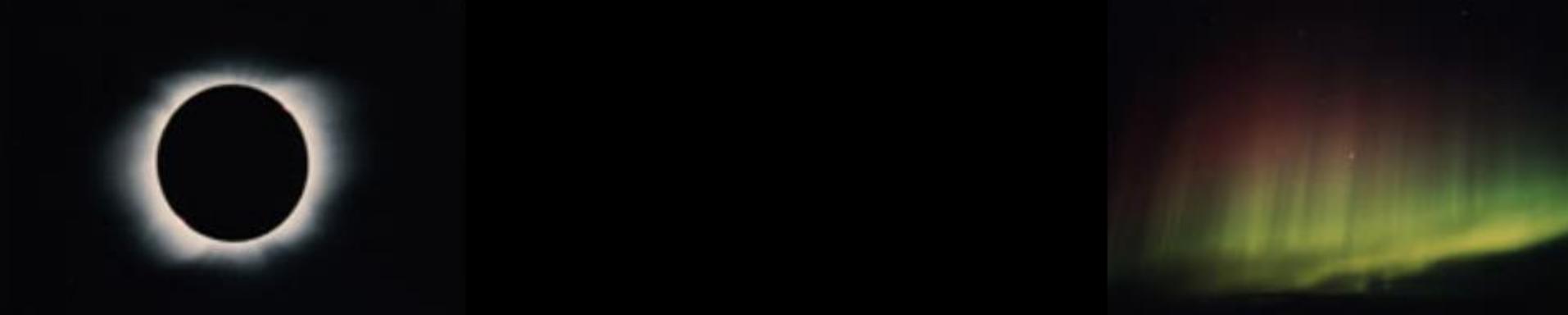




アテナシス (Athenasys Co., Ltd) の ご紹介





会社紹介

<https://athenasys.co.jp/>

設立：2008年 10月 1日

事業内容：ライセンス販売・サポート，コンサルティング

取り扱っている製品とパートナー会社

Bosprom : プラズマシミュレーションで必要となる

輸送係数・反応レートの計算ツール（自社製品）

CFD-ACE+ : マルチフィジックスソフトウェア

CFD-TOPO : 形状シミュレーター

* 日本ESI（販売元）のエージェント

QEC : 分子に対する電子衝突断面積の計算ツール

QDB : プラズマシミュレーションで必要となる反応データベース

* Quantemol（開発元）の国内代理店

重点分野：

熱放射を含む熱流体解析全般

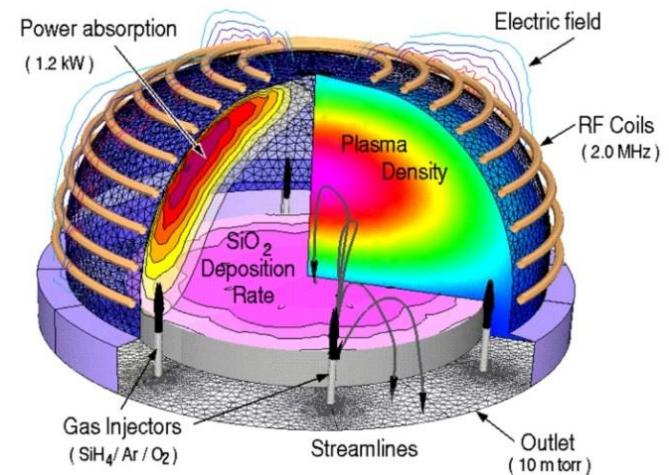
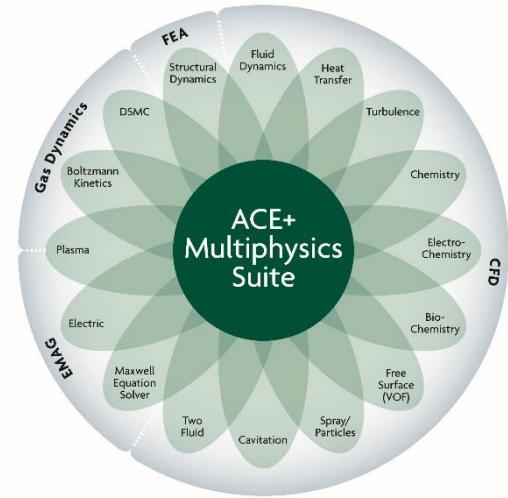
半導体製造装置のプロセスシミュレーション

主要なお客様：

半導体製造装置メーカー，デバイスマーカー

自動車メーカー

担当者はアネルバ（現キヤノンアネルバ）で半導体製造装置の研究開発に長年従事





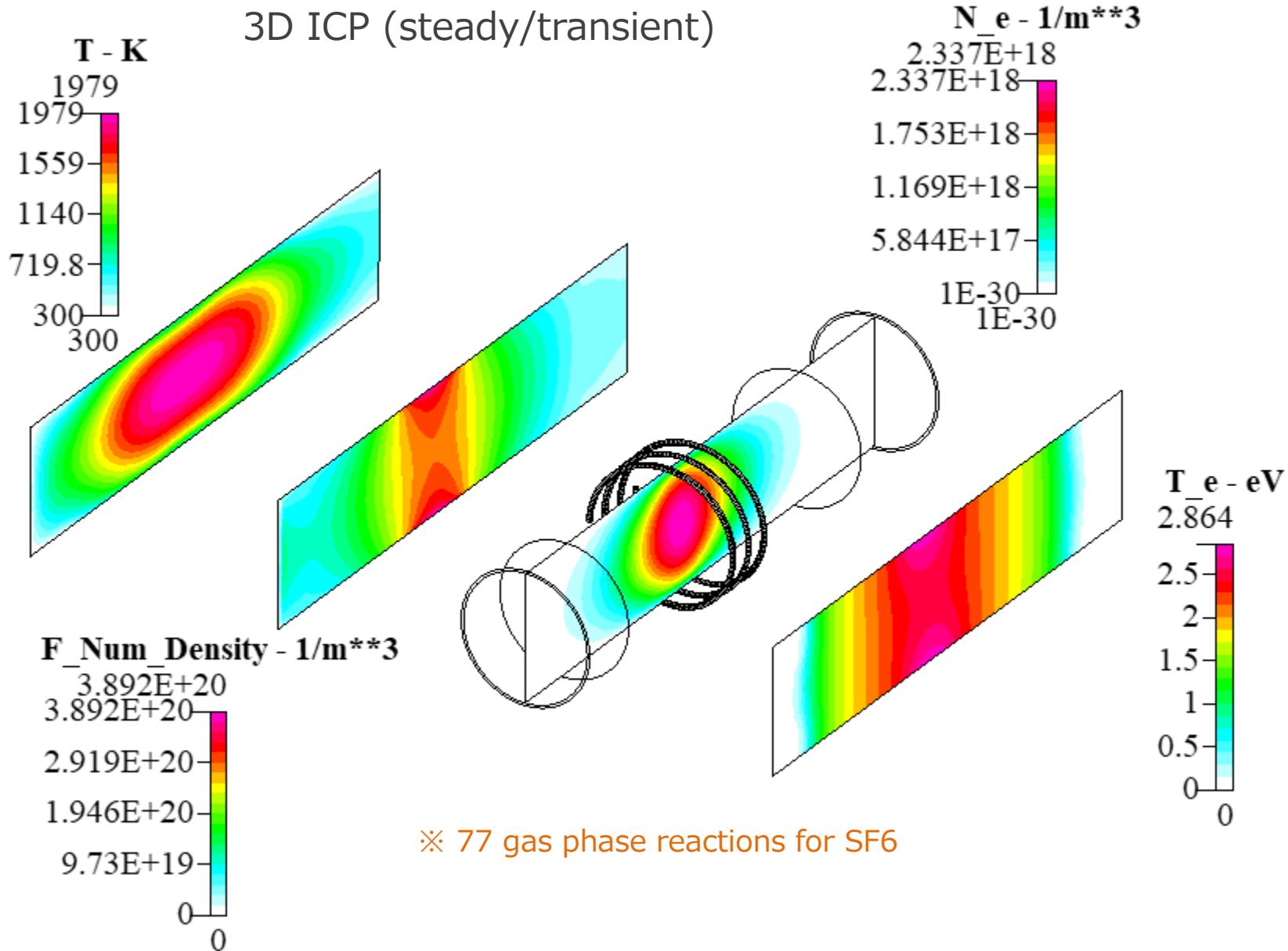
マルチフィジックス ソフトウェア

CFD-ACE+ Suite



Application examples

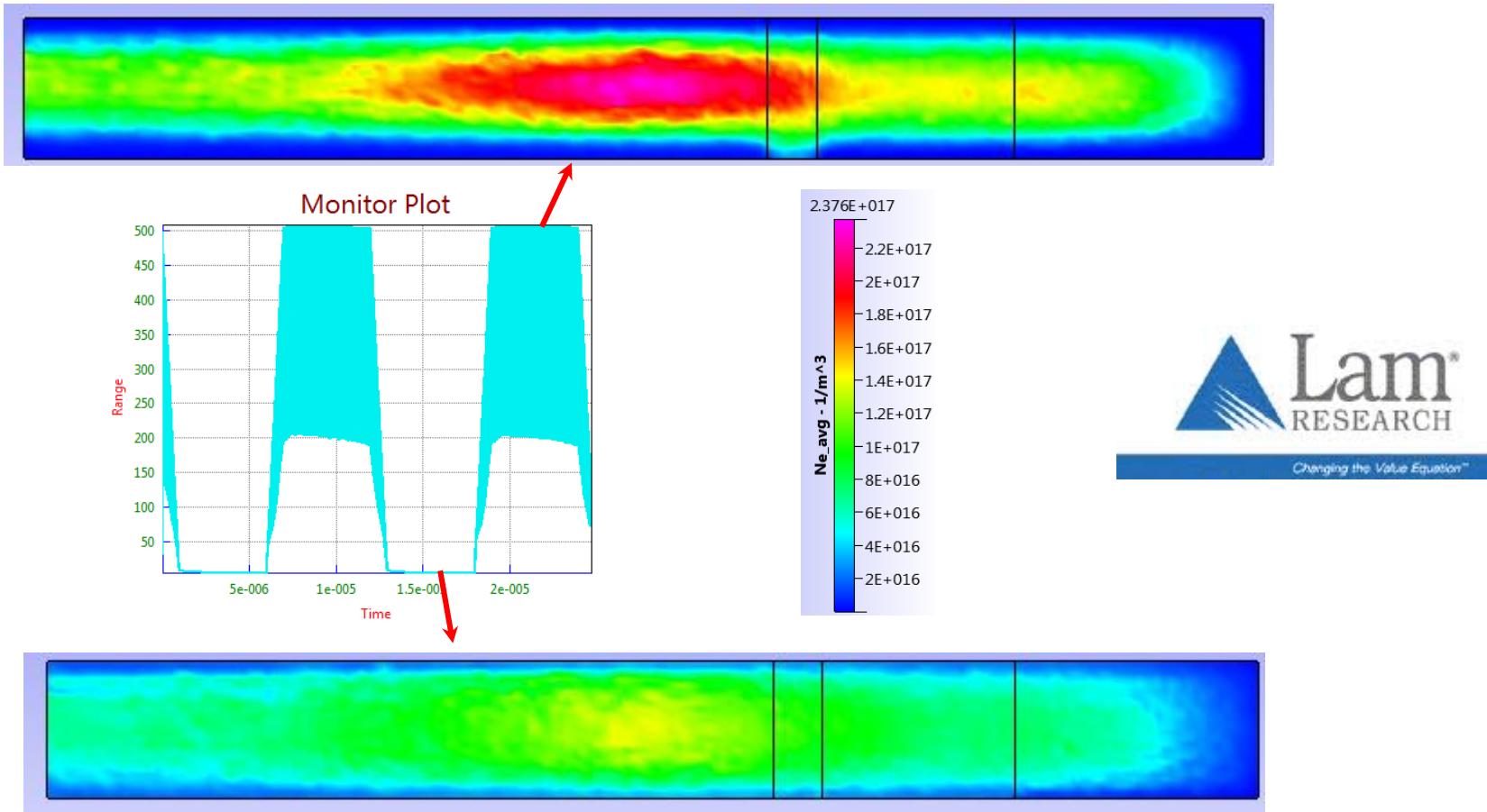
✓ *Low pressure*





Application examples (cont.)

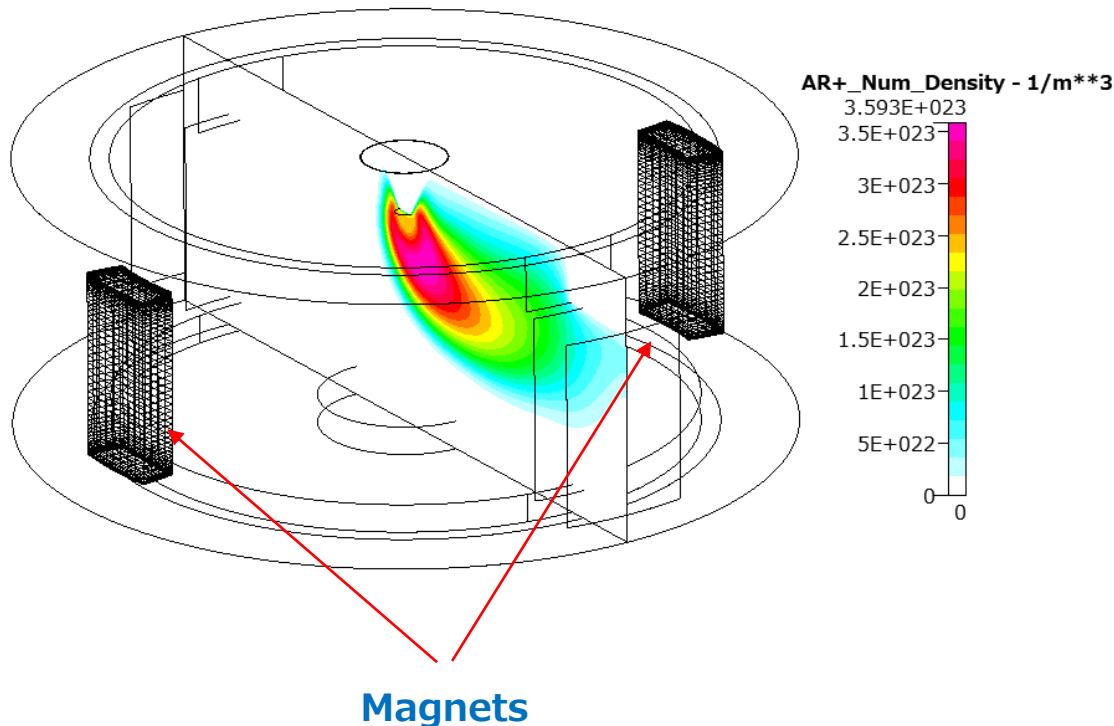
✓ *Pulsed CCP*





Application examples (cont.)

DC Arc (with Lorentz force)



✓ *Atmospheric pressure
(and higher pressure)*

Dielectric Barrier Discharge

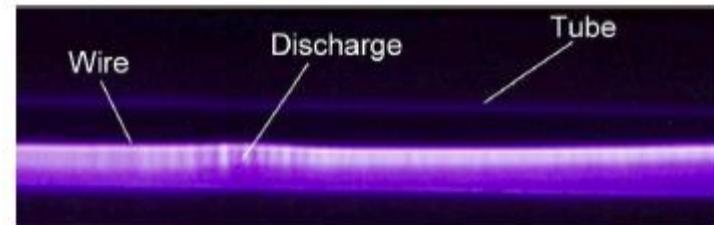


Fig. 2 Side view of the DBD in the tube

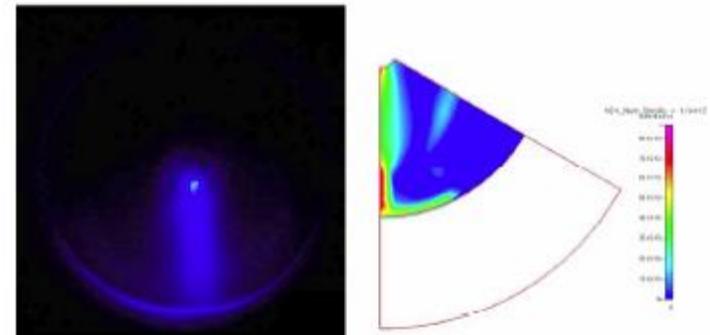


Fig.3 Spectrum photograph through band-pass filter of 450 nm (half-width: 10 nm)

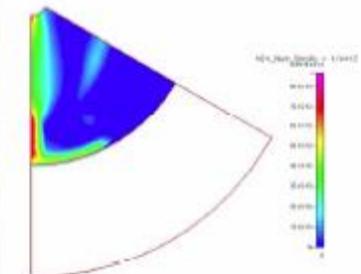


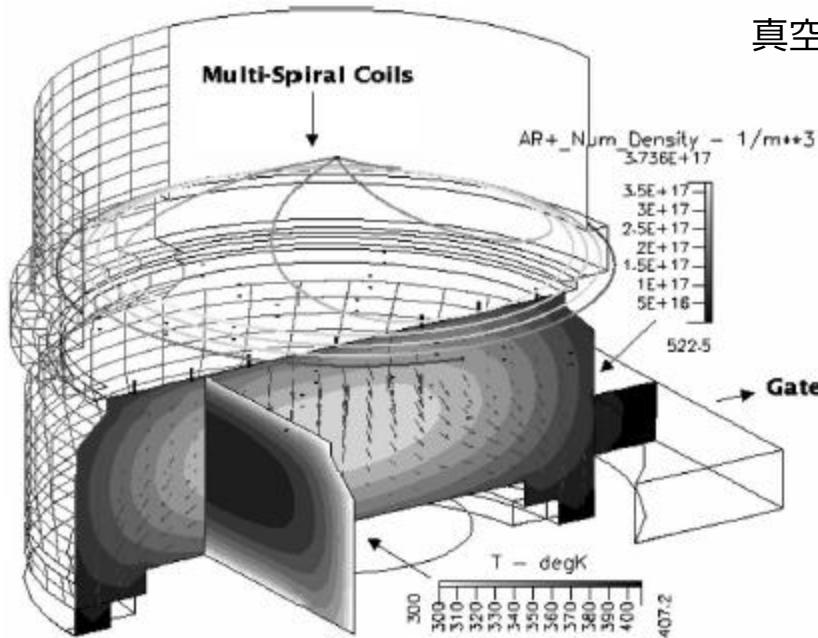
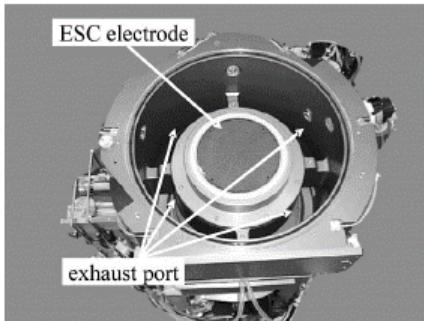
Fig.4 Distribution of number density of the N_2^+ .

Takehiko Sato, Osamu Furuya, Kei Ikeda and Tatsuyuki Nakatani
1st International Conference on Plasma Medicine (ICPM-1),
Corpus Christi, Texas, (2007) pp. 48-50



Application examples (cont.)

✓ **3-D**
(with filament model)



✓ **Magnetized Plasma**

JIEED Japan Vol.57 No.3 (2014) p.27
(放電学会シンポジウム)

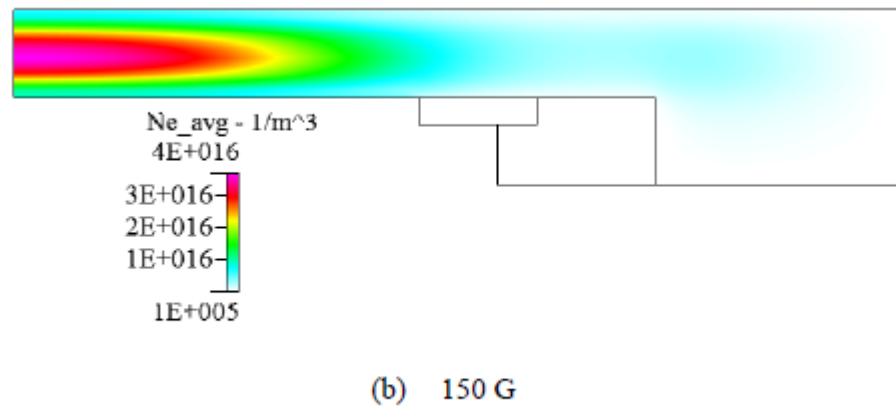


Fig. 3. Cycle-averaged electron number density.



Application examples for plasma (cont.)

Self-consistent kinetic model coupling the Boltzmann and Poisson equations

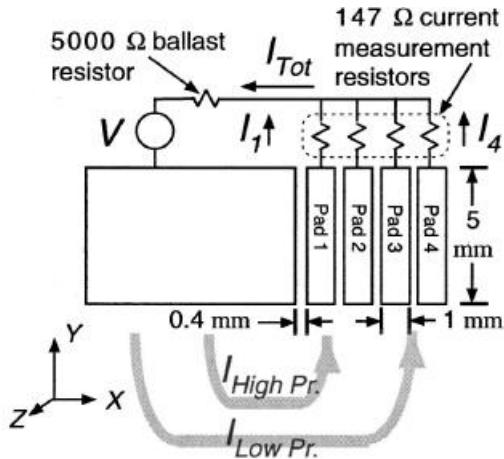


FIG. 1. Planar Ti electrode configuration, patterned on glass to measure cathode current density. Cathode is split into separate paths, where the current is independently measured. Polarity can be reversed to measure anode current density.

Profiling and modeling of dc nitrogen microplasmas
Wilson et al. J. Appl. Phys., 94 (2003) 2845

❖ Kinetic solver :

Four dimensional Fokker–Planck solver for electron kinetics in collisional gas discharge plasmas

V. Kolobov, R. Arslanbekov / Computer Physics Communications 164 (2004) 195–201

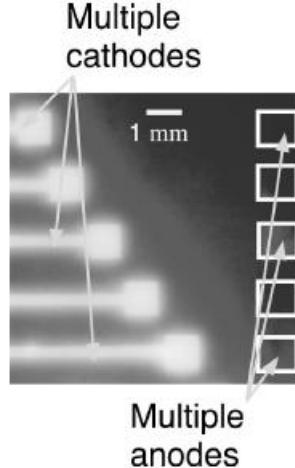


FIG. 4. Microplasmas generated at 2 Torr, in air, at 423 V. The microplasma glow region is confined over the cathode, and is independent of the anode–cathode spacing.

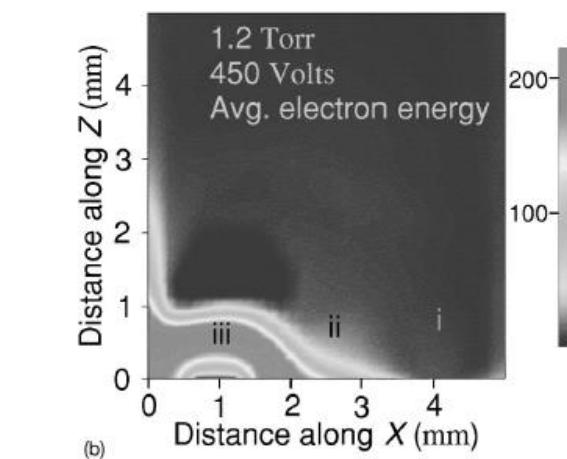
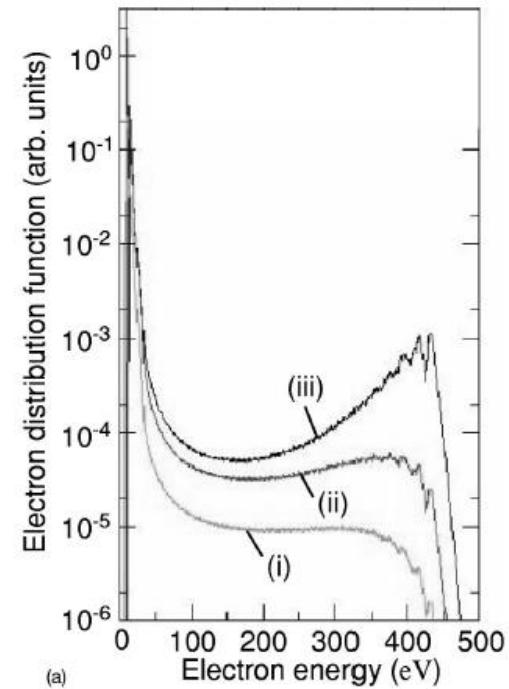


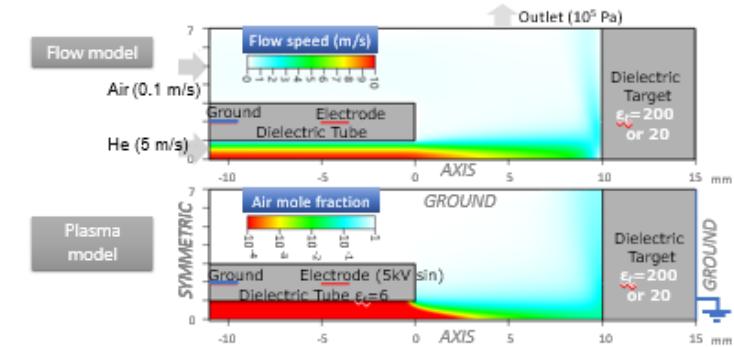
FIG. 13. Modeled electron energy distribution function has bimodal nature near the cathode.



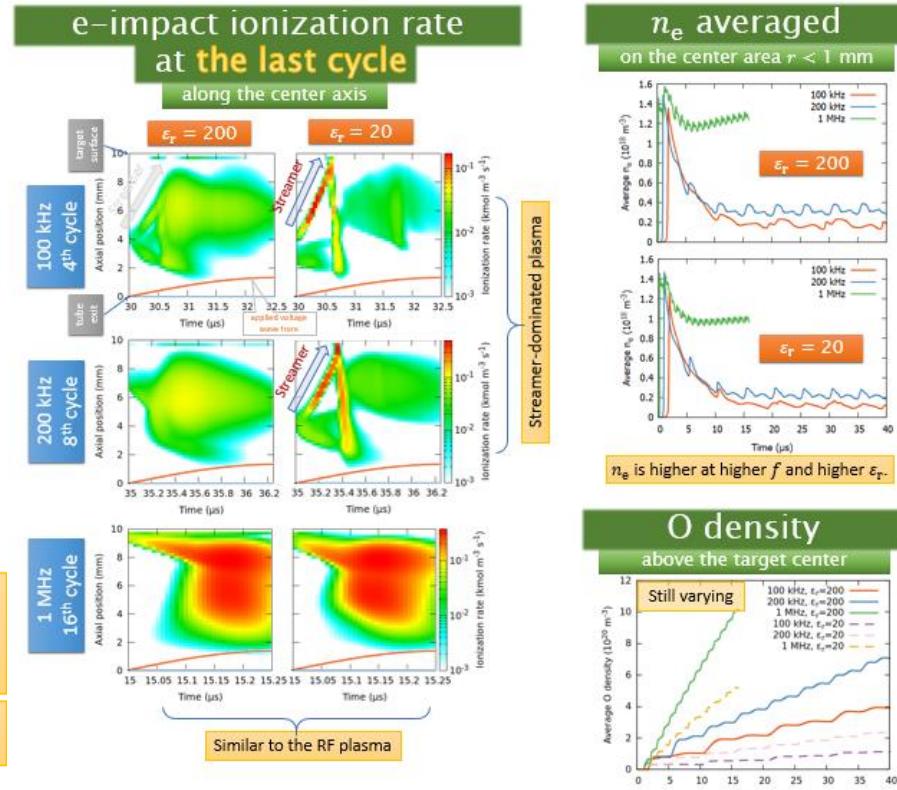
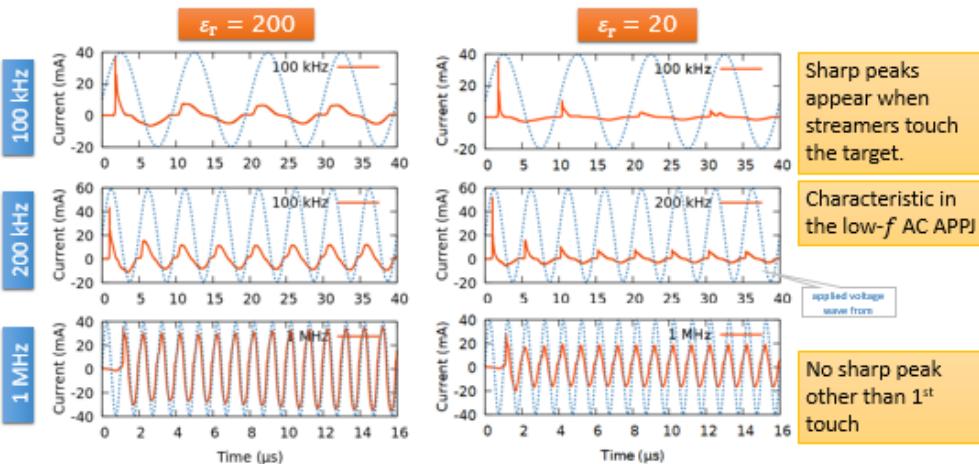
Application examples for plasma (cont.)

Modeling study on AC atmospheric pressure He plasma jets interacting with a dielectric target

DPS 2019 (by Kobayashi)



- Sequence: Gas flow model → Plasma model with fixing the gas flow
- Chemistry: 20 species and 80 reactions
- EEDF: Maxwellian
- Surface O destruction $\gamma = 0.02$, SEEC $\gamma = 0.1$
- Seed electrons $\sim 2 \times 10^{13} \text{ m}^{-3}$ (instead of photoionization)
- Gas temperature = 300 K (const.)
- Electrode voltage: 5 kV sinusoidal AC at $f = 100 \text{ kHz}, 200 \text{ kHz}, 1\text{MHz}$
- Time integration: up to 4 cycles (100 kHz), 8 cycles (200 kHz), 16 cycles (1 MHz)
- Time step: 20 ps





Application examples for plasma (cont.)

PECVD for Silicon Nitride

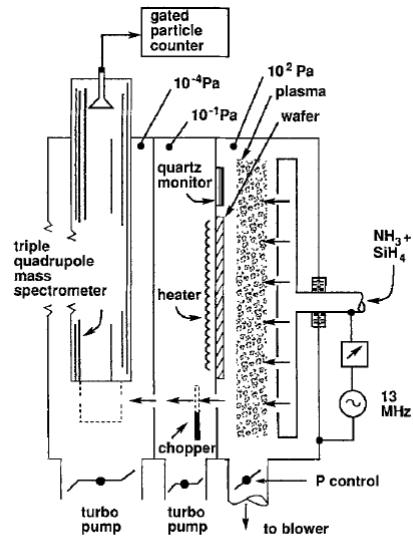
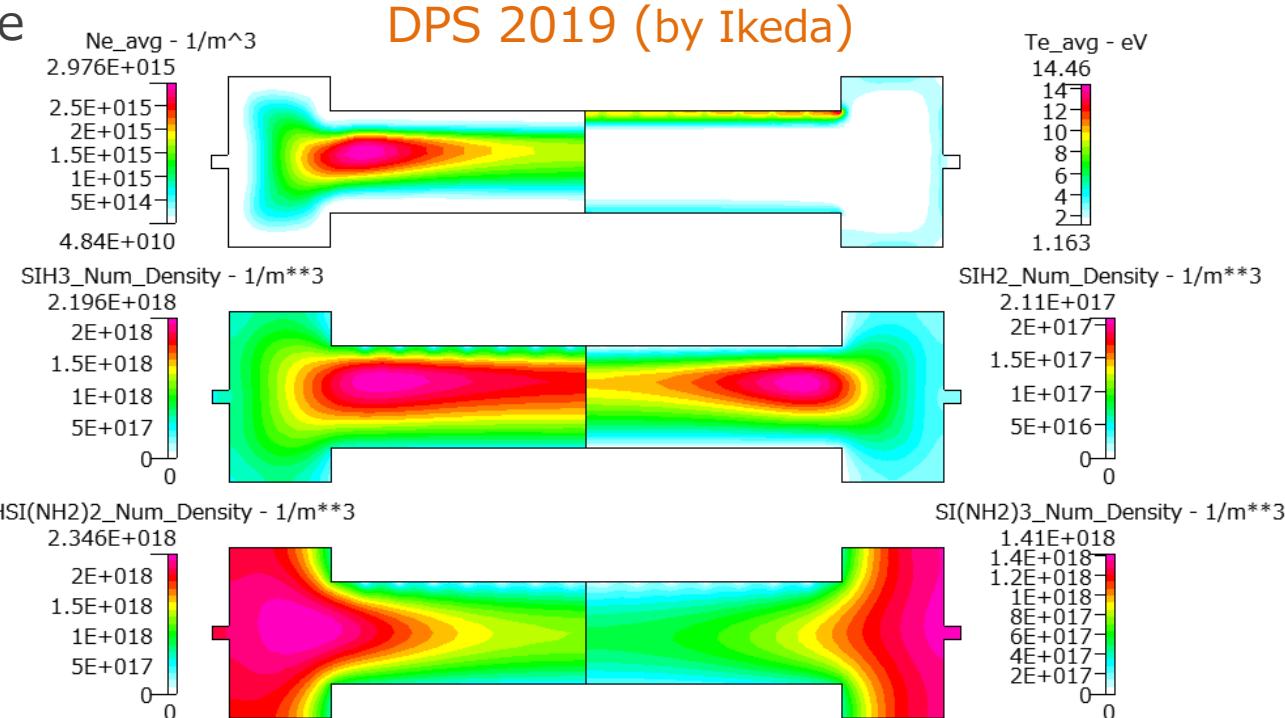
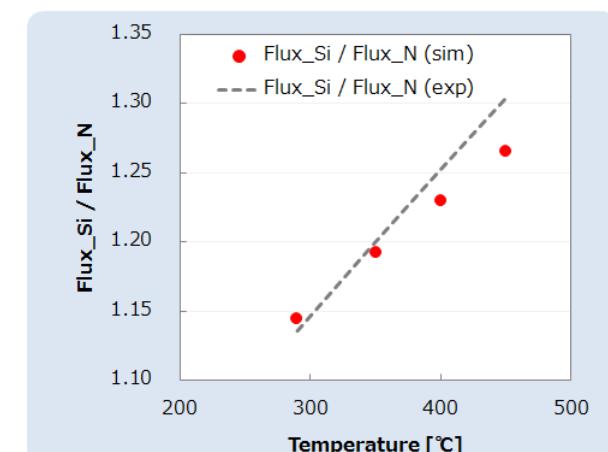
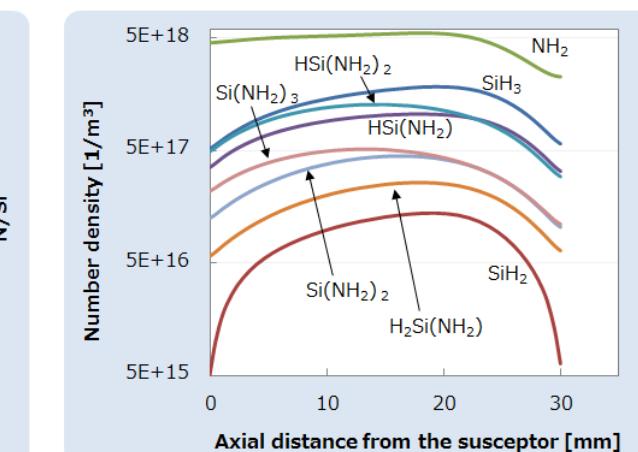
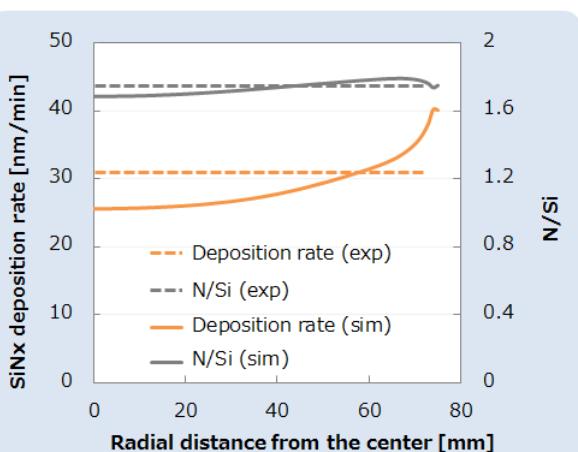


Fig. 1. Plasma reactor and analytical equipment, including quartz deposition monitor in wafer plane and line-of-sight mass spectrometric sampling.





Sheath model (Boundary condition)

Ion energy dependency for the reaction rate and yield can be set when ICP (w/o CCP option) is chosen.

The sheath is not mesh resolved.
Semi-analytic sheath model is used to compute the IEADs at wafer.

The bias needs to be specified: V_{rf} , V_{dc} and Frequency.

Plasma

SubType Sheath Model

Electron Temperature

Thermal Flux Balance

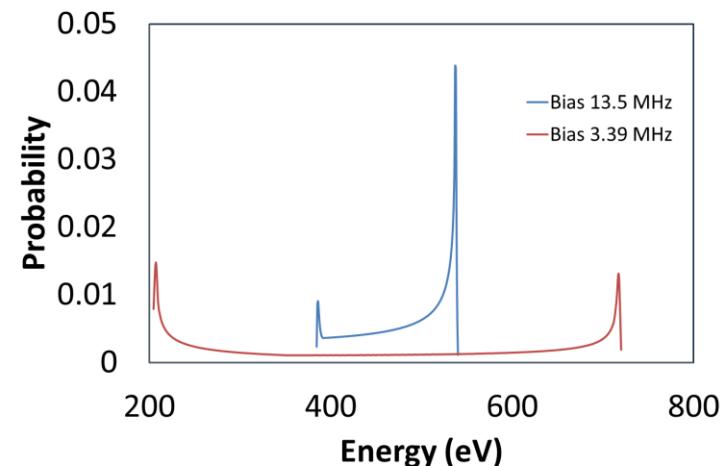
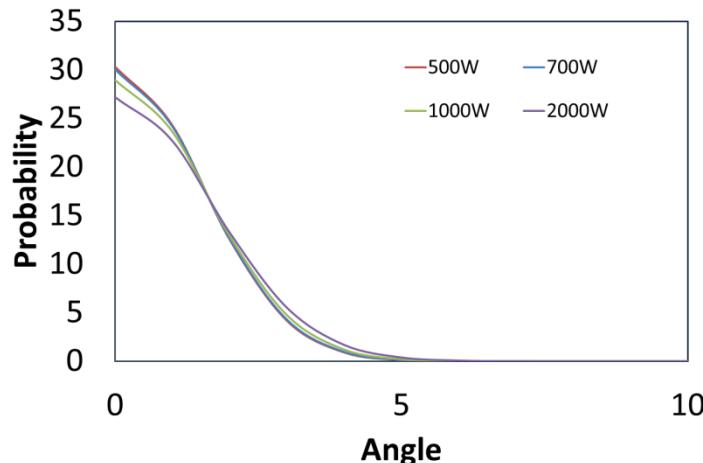
Sheath Model

Bias Frequency 13500000 Hz

Bias Power 0 W

RF Bias 460 V

DC Bias -45 V





Monte Carlo to compute IEADFs

Characterization of an asymmetric parallel plate radio-frequency discharge using a retarding field energy analyzer

Plasma Sources Sci. Technol. 21 (2012) 015002

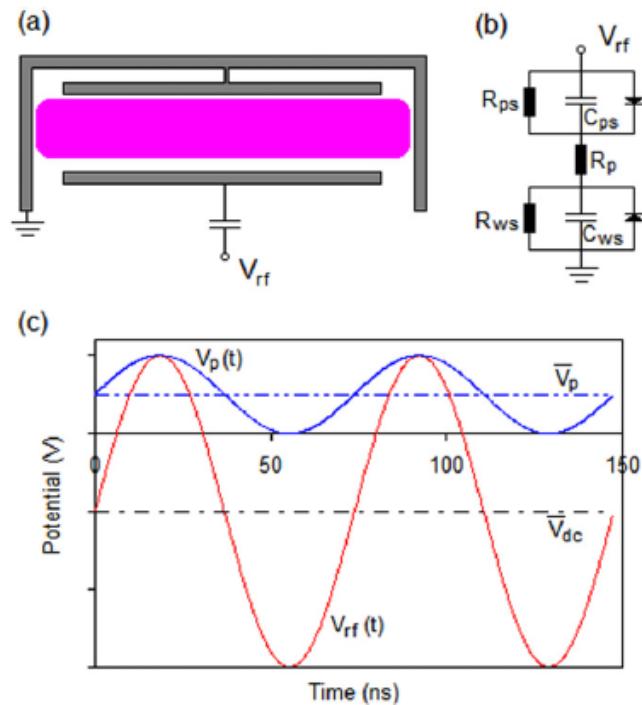


Figure 3. (a) Schematic of capacitively coupled asymmetric rf discharge, (b) equivalent circuit where R_{ps} and C_{ps} are the powered sheath resistance and capacitance, respectively, and R_{ws} and C_{ws} are the wall/ground sheath resistance and capacitance, respectively. R_p is the bulk plasma resistance, (c) illustrative discharge potentials where $V_{rf}(t)$ and \bar{V}_{dc} are the excitation potential and dc self-bias, respectively, and $V_p(t)$ and \bar{V}_p are the time-varying and time-averaged components of the plasma potential, respectively.

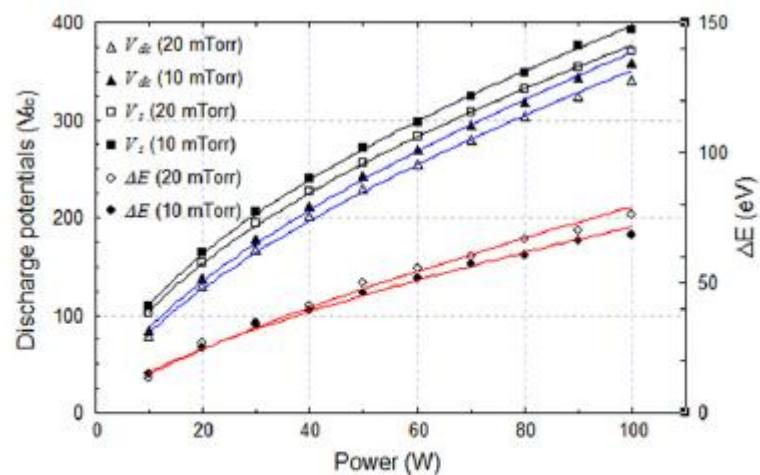
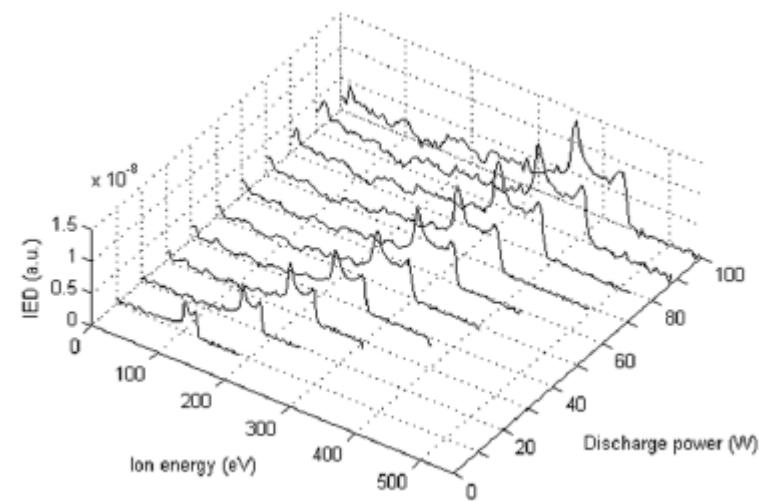


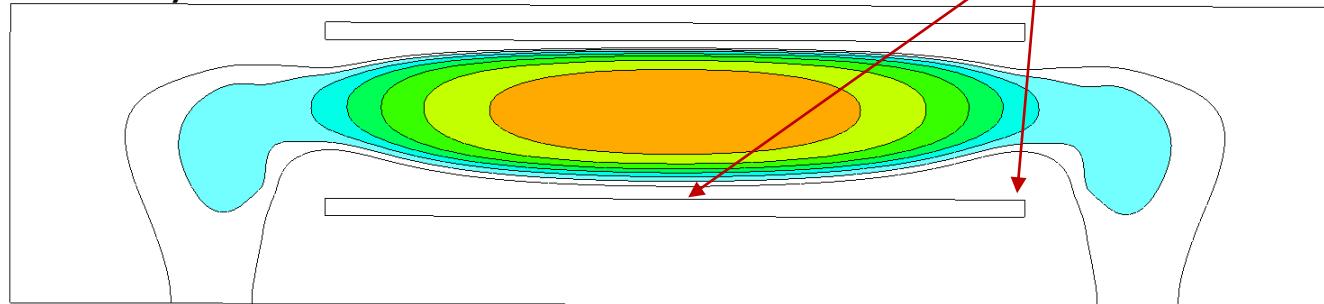
Figure 6. Self-bias voltage (measured directly), time-averaged sheath potential and collisionless ion peak separation (calculated from the IED measurements) as a function of power and pressure.



Monte Carlo to compute IEADFs (2)

Specify positions to compute IEADF

Electron Density

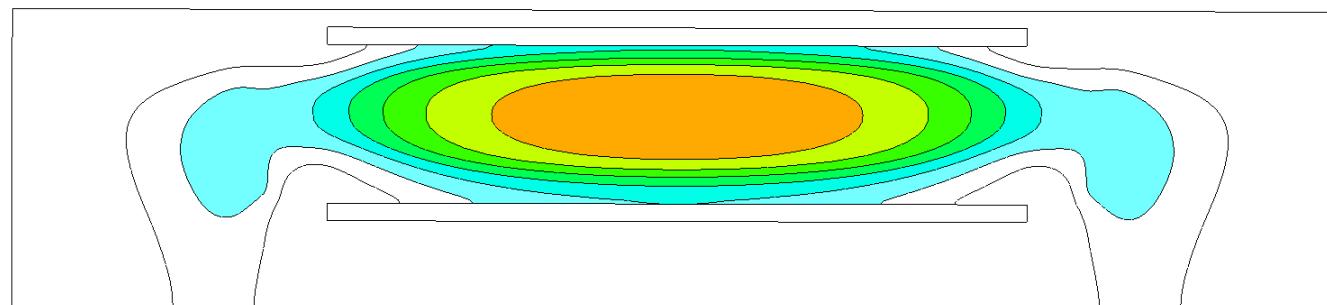


Plasma

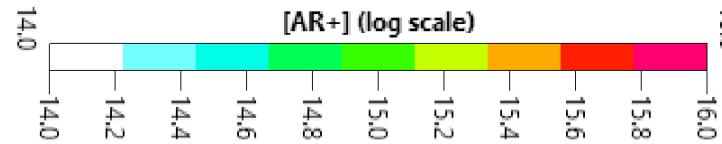
Monte Carlo Transport

Select Locations for IEADF Computation ...

Ar+ Density



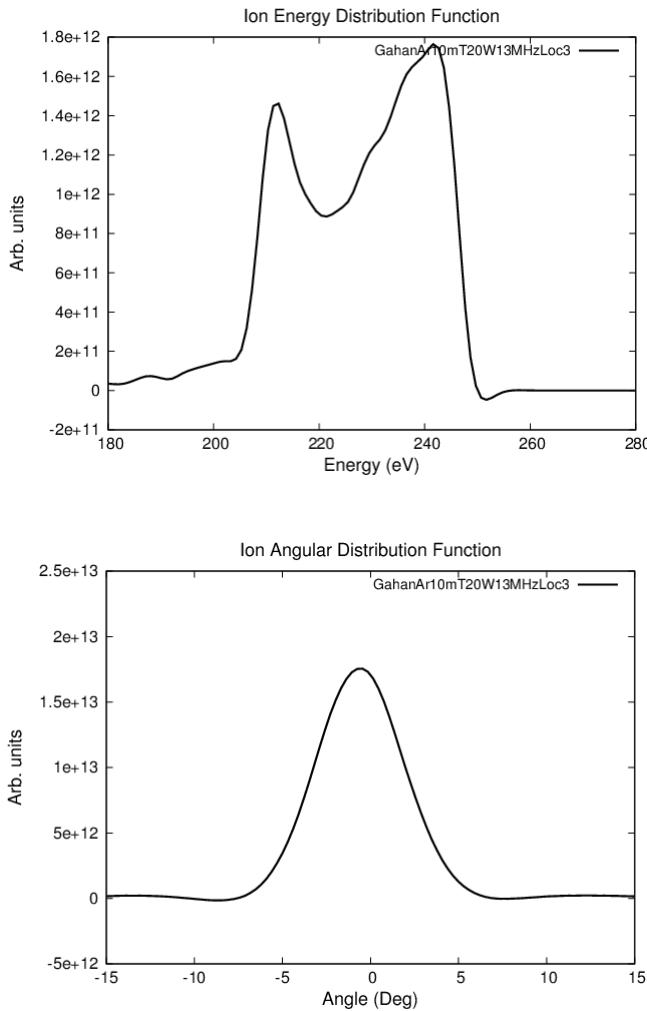
Conditions:
Ar 10 mTorr
20 W, 13MHz



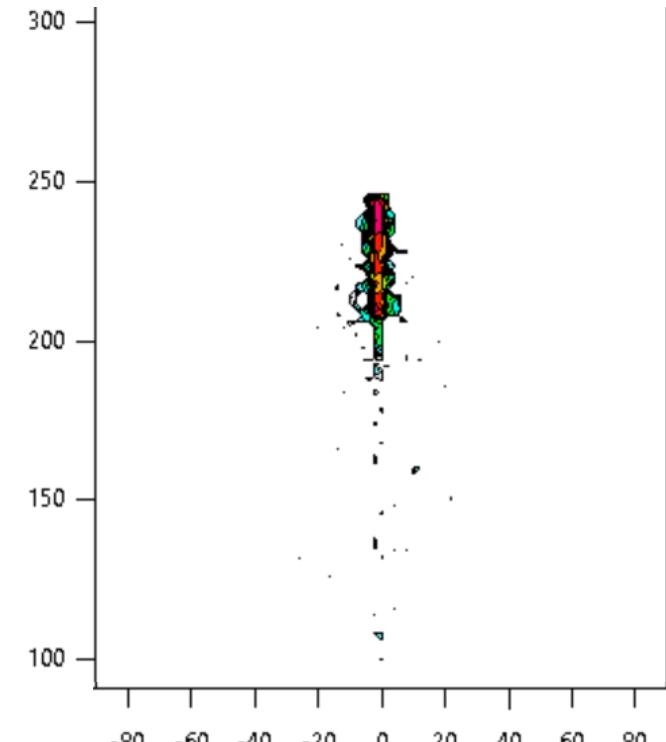
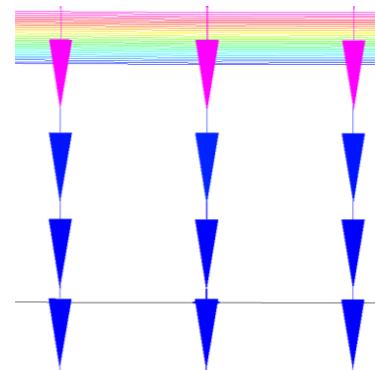


Monte Carlo to compute IEADFs (3)

Position : Wafer center



Ion Flux



Monte Carlo Computation:

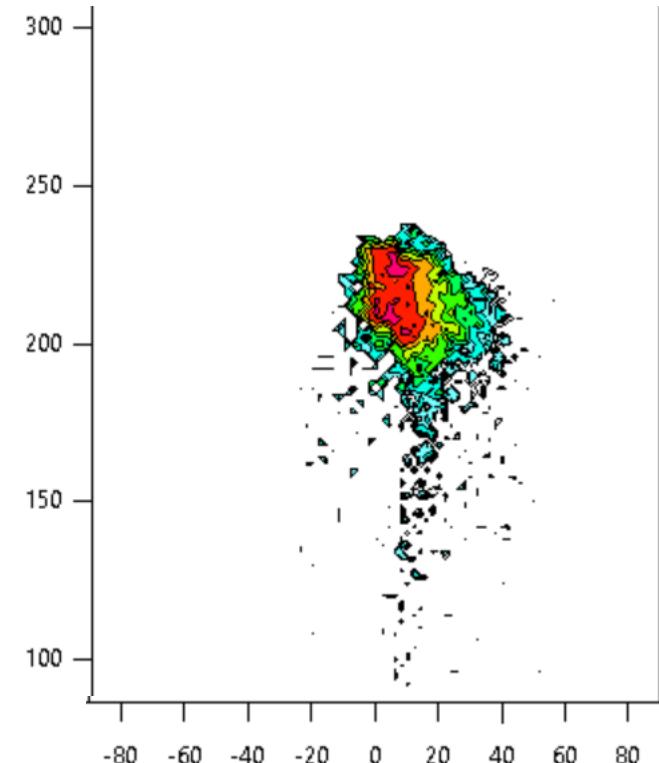
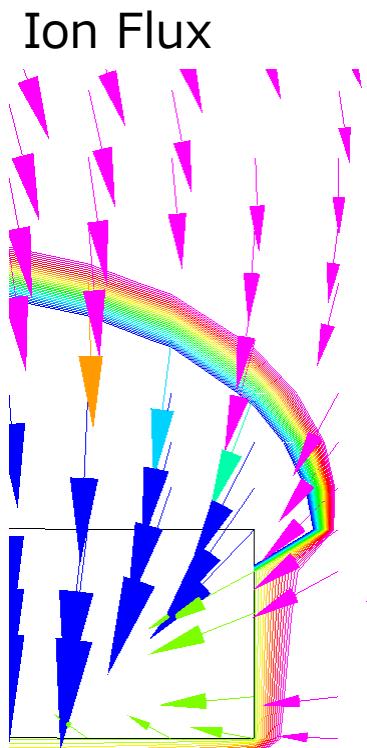
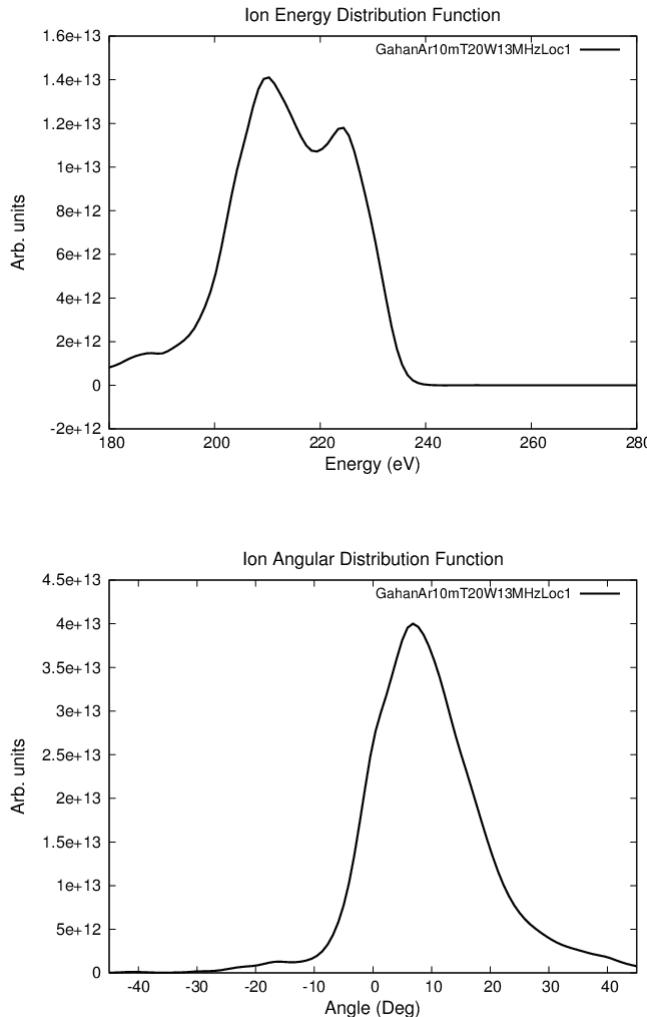
$$E_{\text{low}} \sim 210 \text{ eV}$$

$$E_{\text{high}} \sim 242 \text{ eV}$$



Monte Carlo to compute IEADFs (4)

Position : Wafer edge

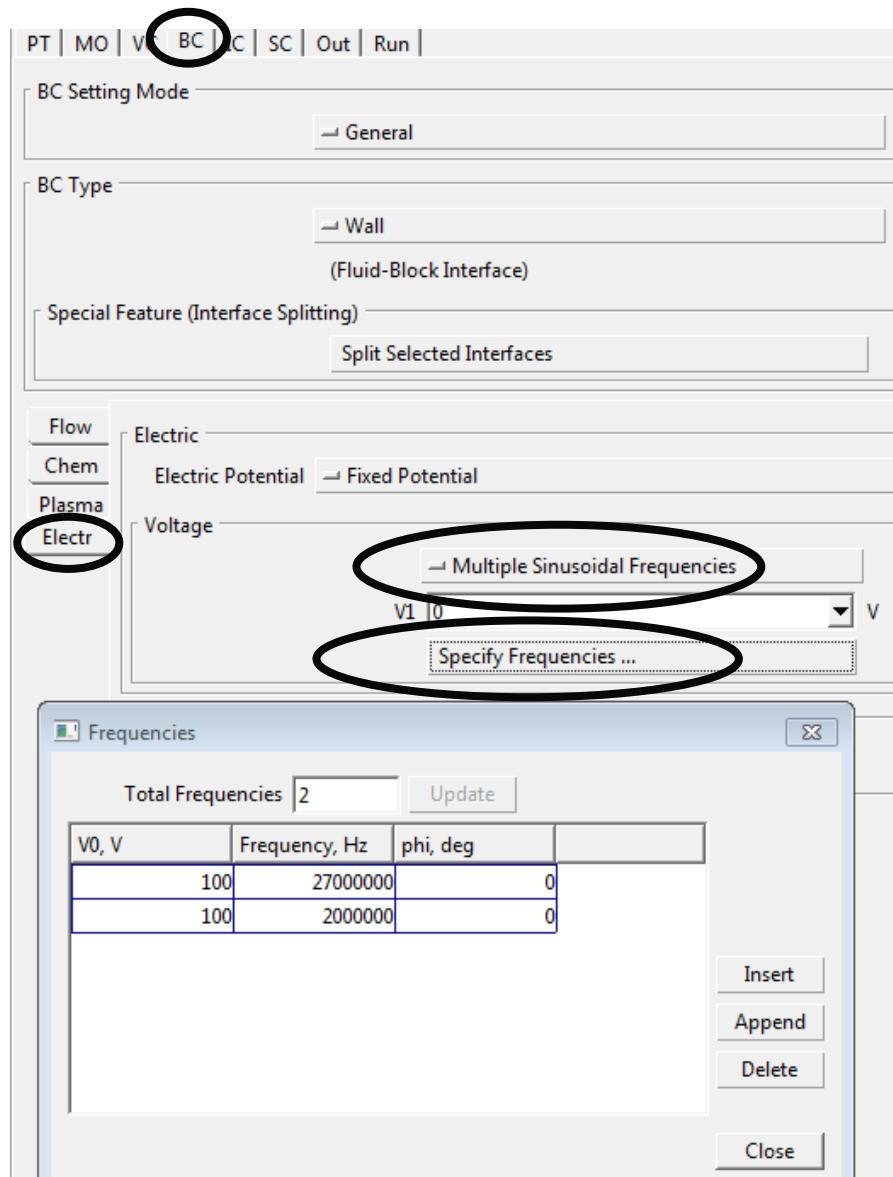
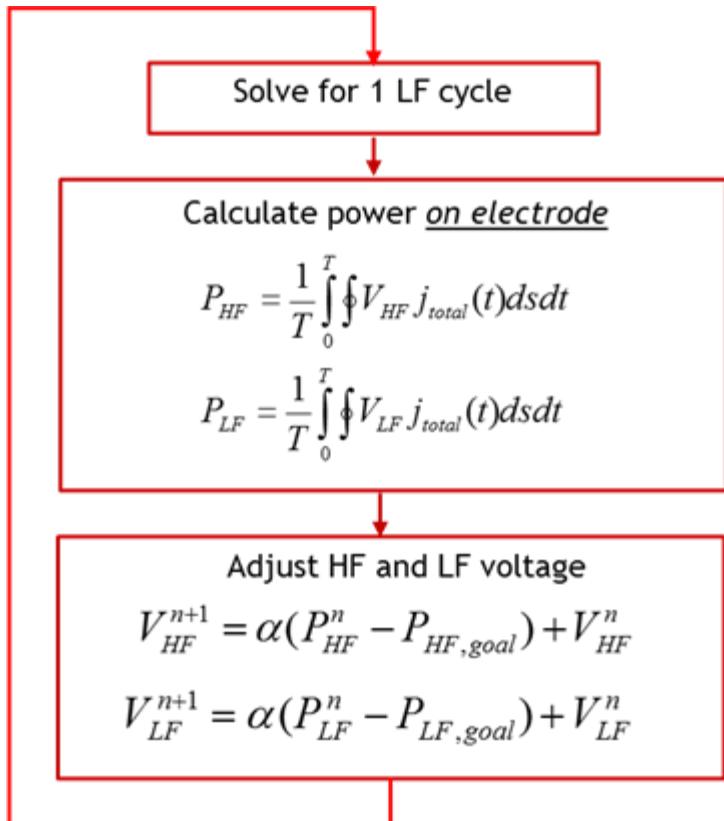


Monte Carlo Computation:
 $E_{low} \sim 210 \text{ eV}$
 $E_{high} \sim 226 \text{ eV}$



Multi-frequency CCP

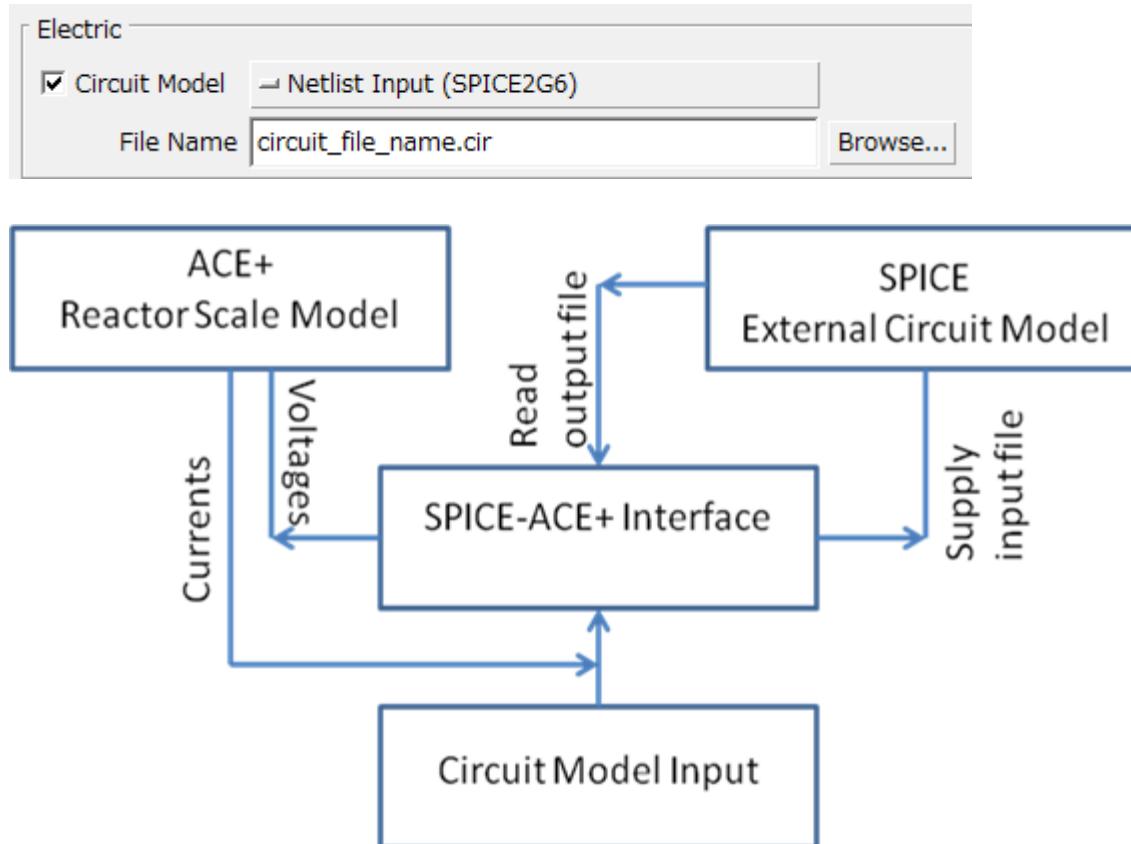
Dual frequency on one electrode can be set easily





Spice coupling

CFD-ACE+ Plasma solver accounts for **external circuit** interactions to a greater degree of generality. Proposed external circuit coupling to **SPICE** will enable generic circuit representations at several reactor surfaces.





形状シミュレータ

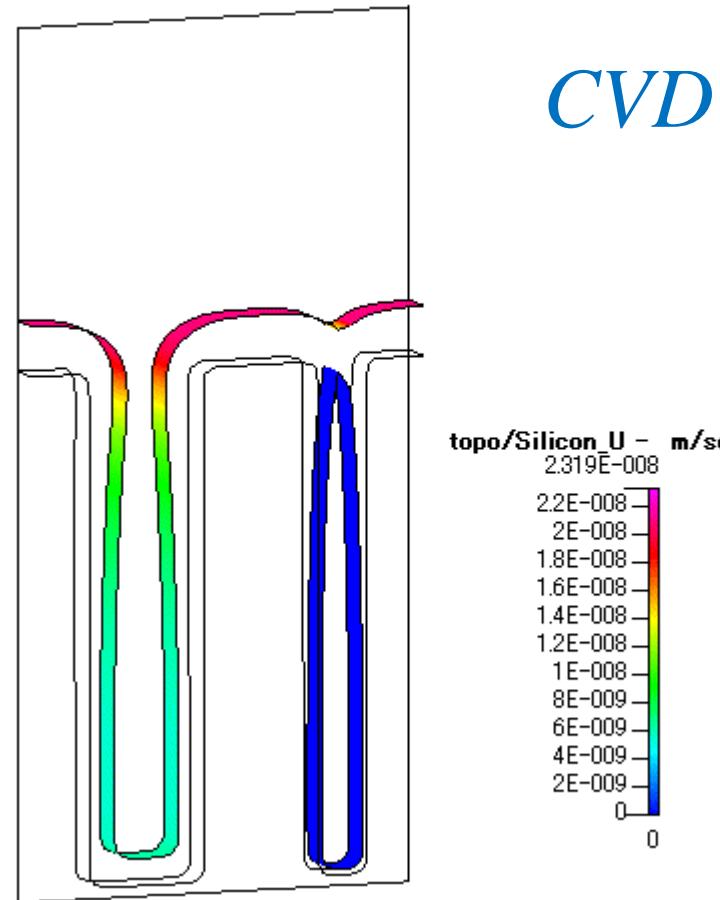
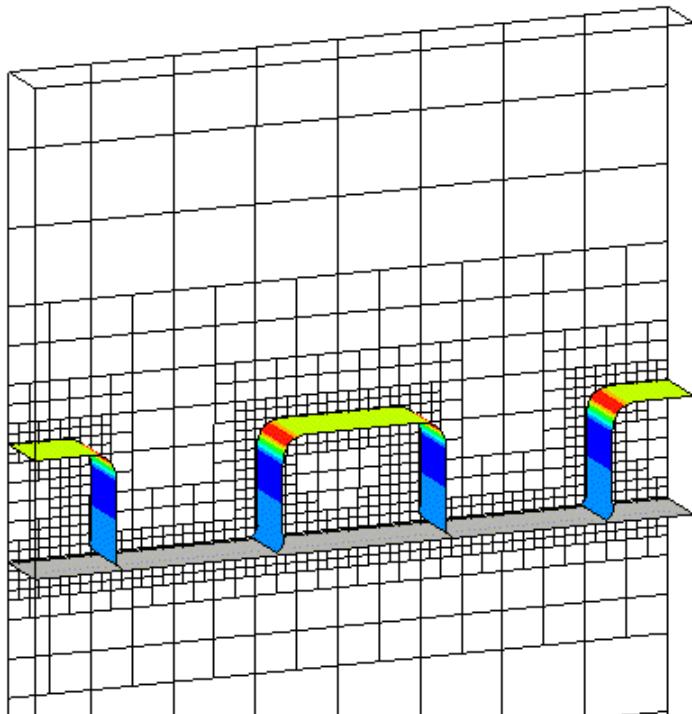
CFD-TOPO



Topology simulation by CFD-TOPO

※ Input file can be obtained by CFD-ACE+

Etching



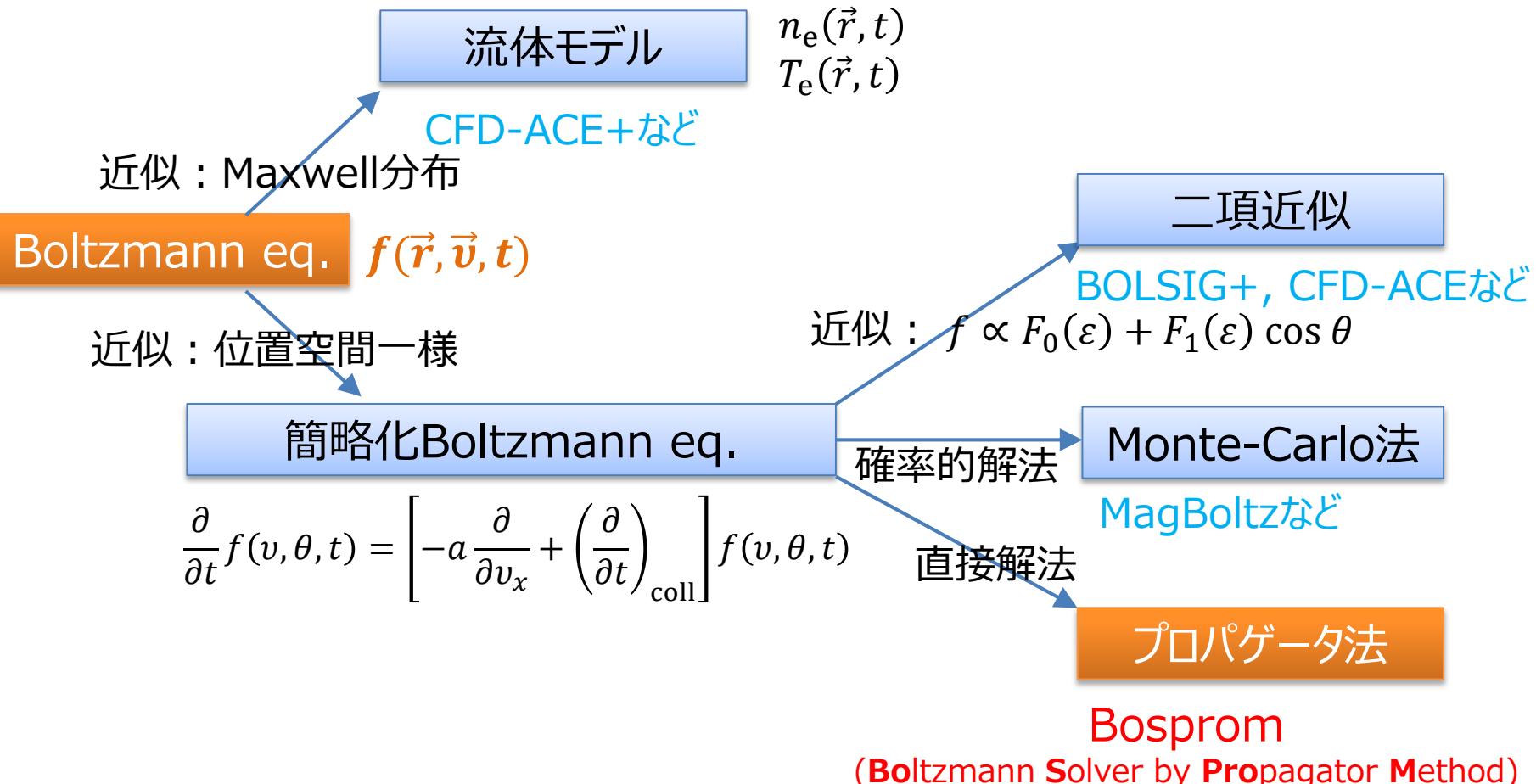


Swarm パラメータ, 反応レート
の Lookup Table 作成ツール

Bosprom



プロパゲータ法 (分布関数 $f(\vec{v})$ 計算法の一種)

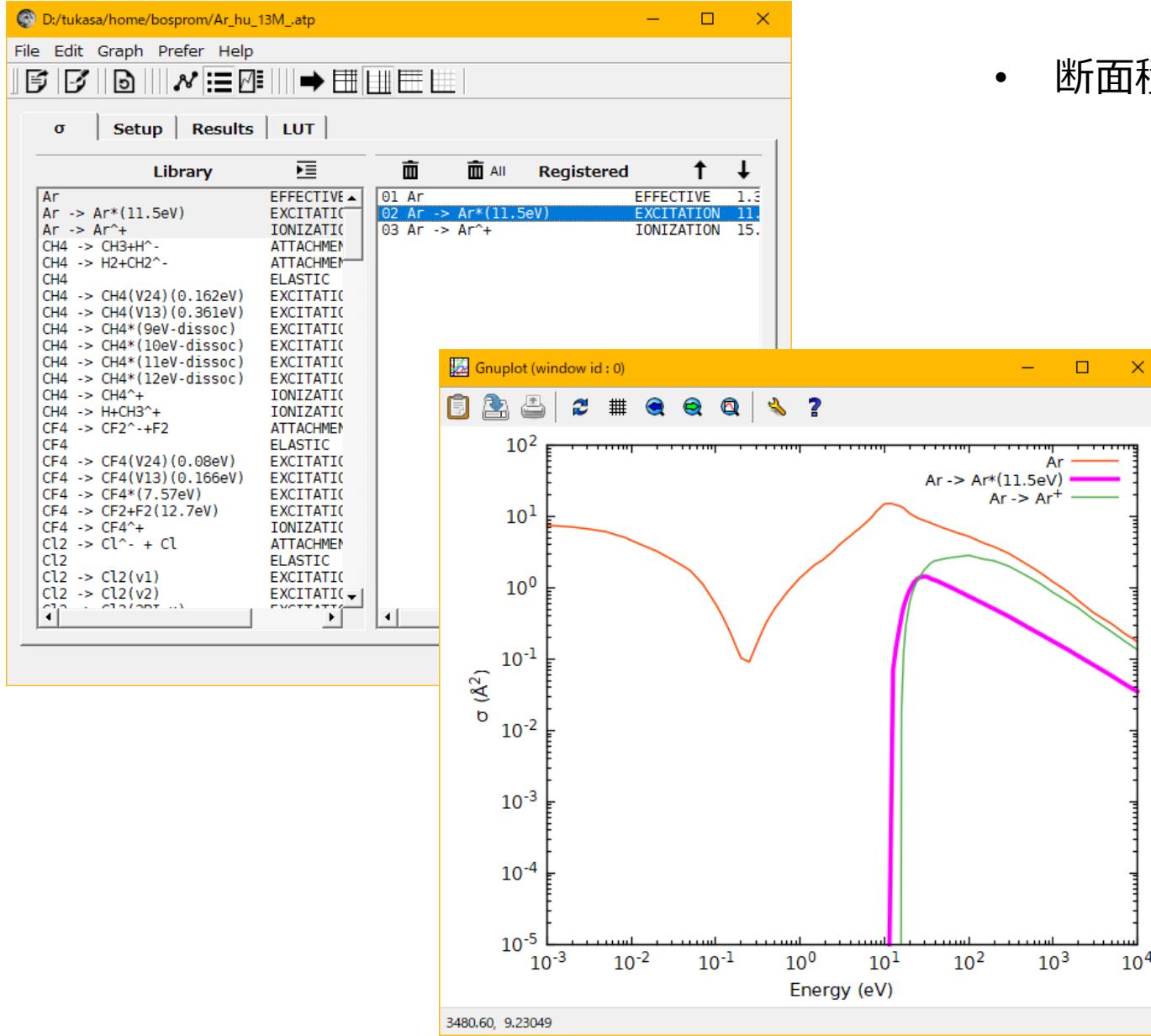


衝突断面積 → 分布関数 f → 反応レート定数, 輸送係数(移動度, 拡散係数)

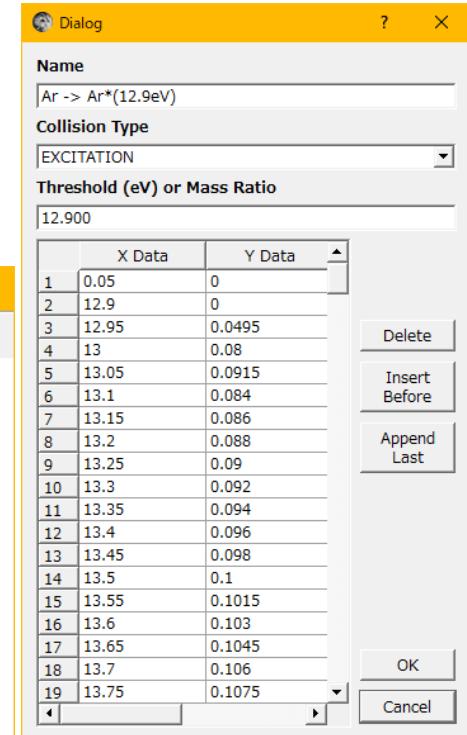
Swarm parameters



Bosprom:衝突断面積データ選択・編集画面

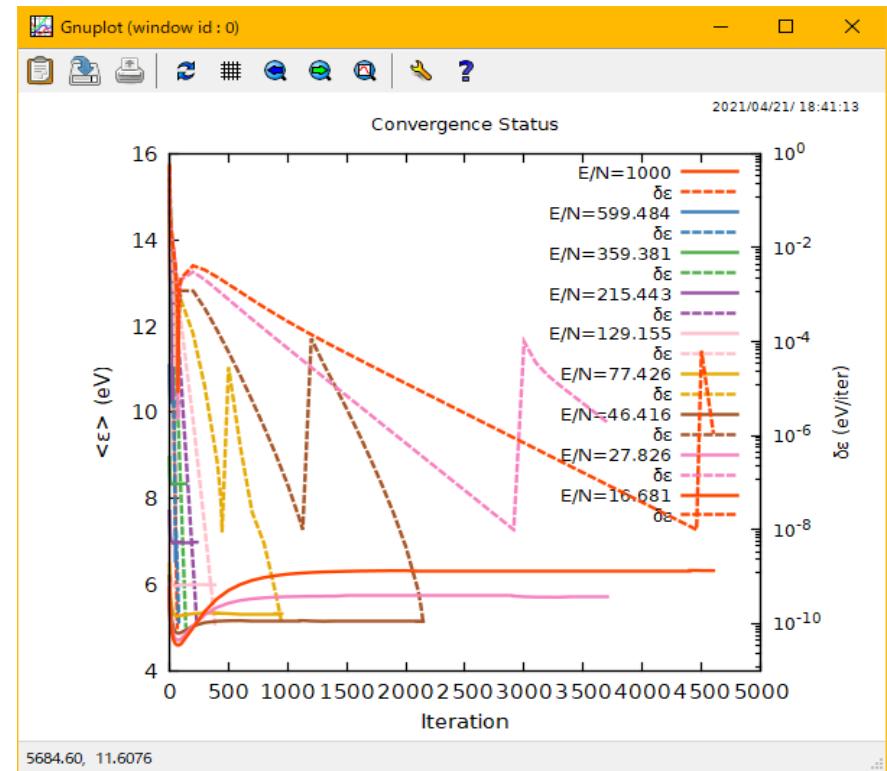
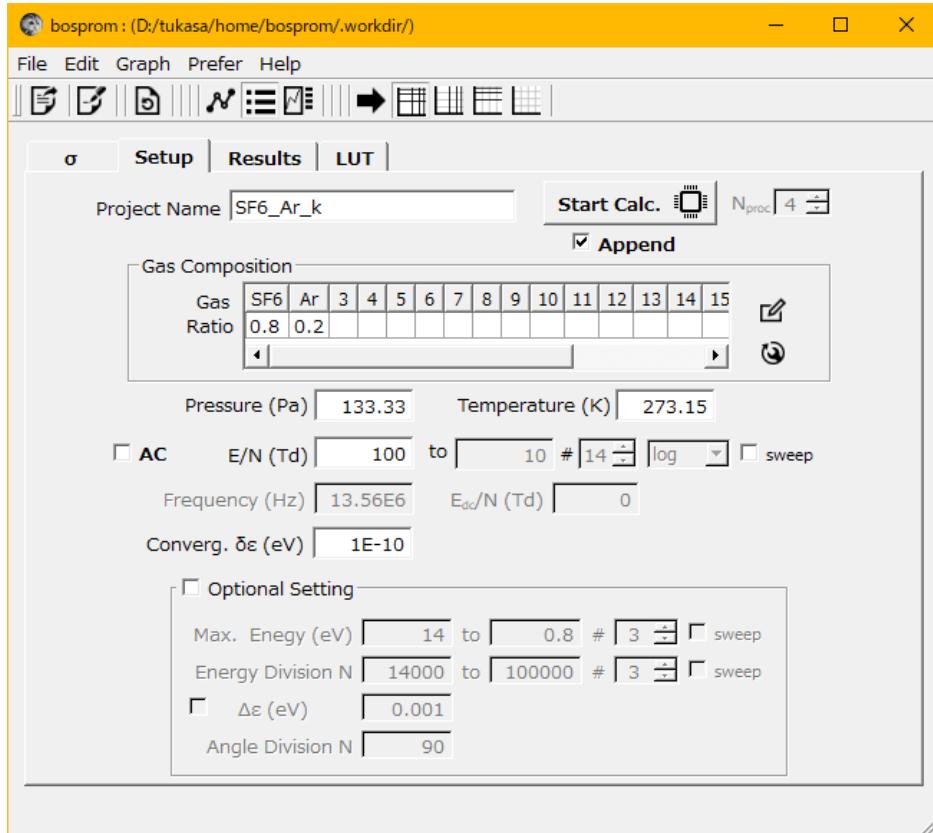


- 断面積データの編集が可能



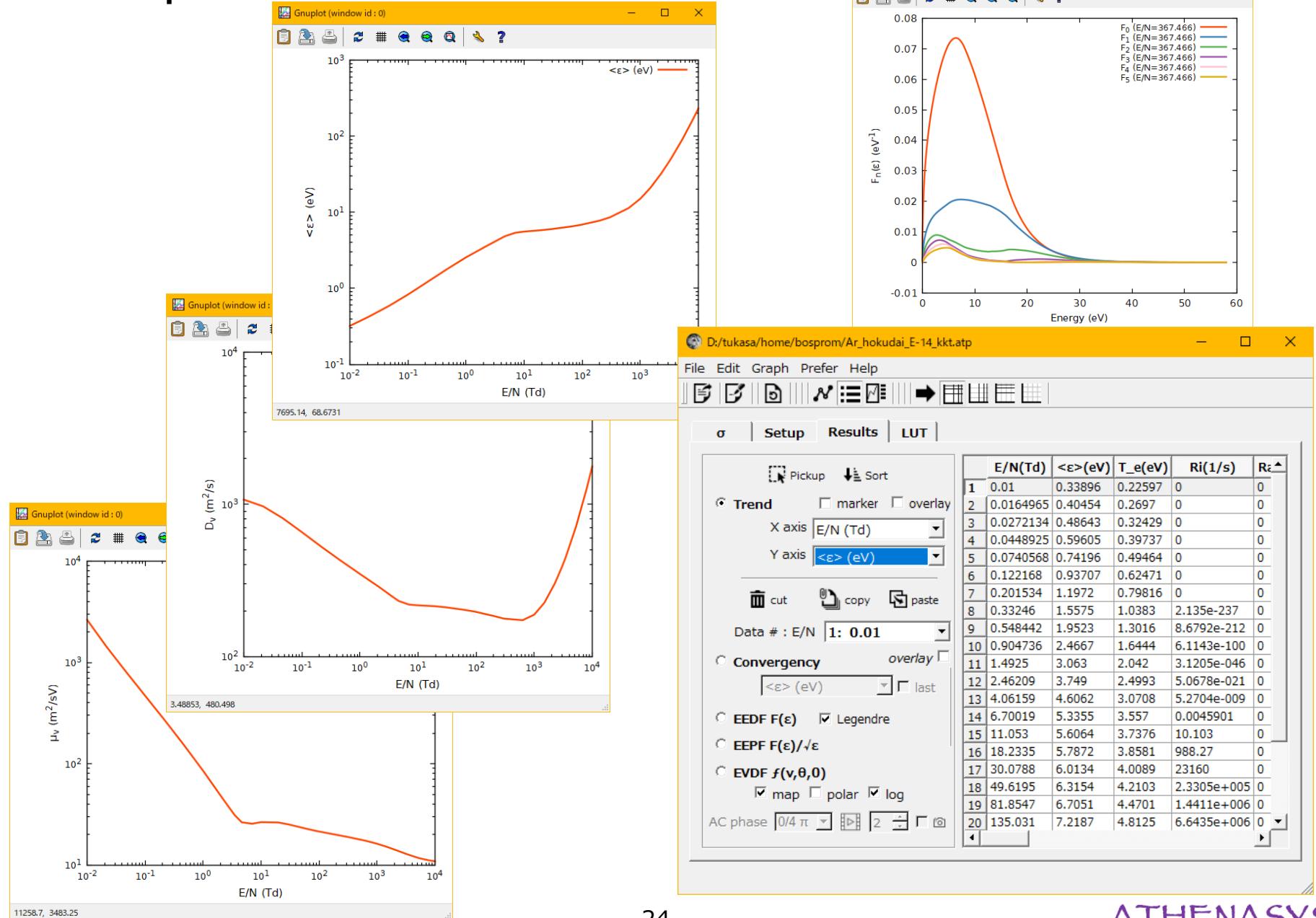


Bosprom: 計算条件設定画面・収束状況表示



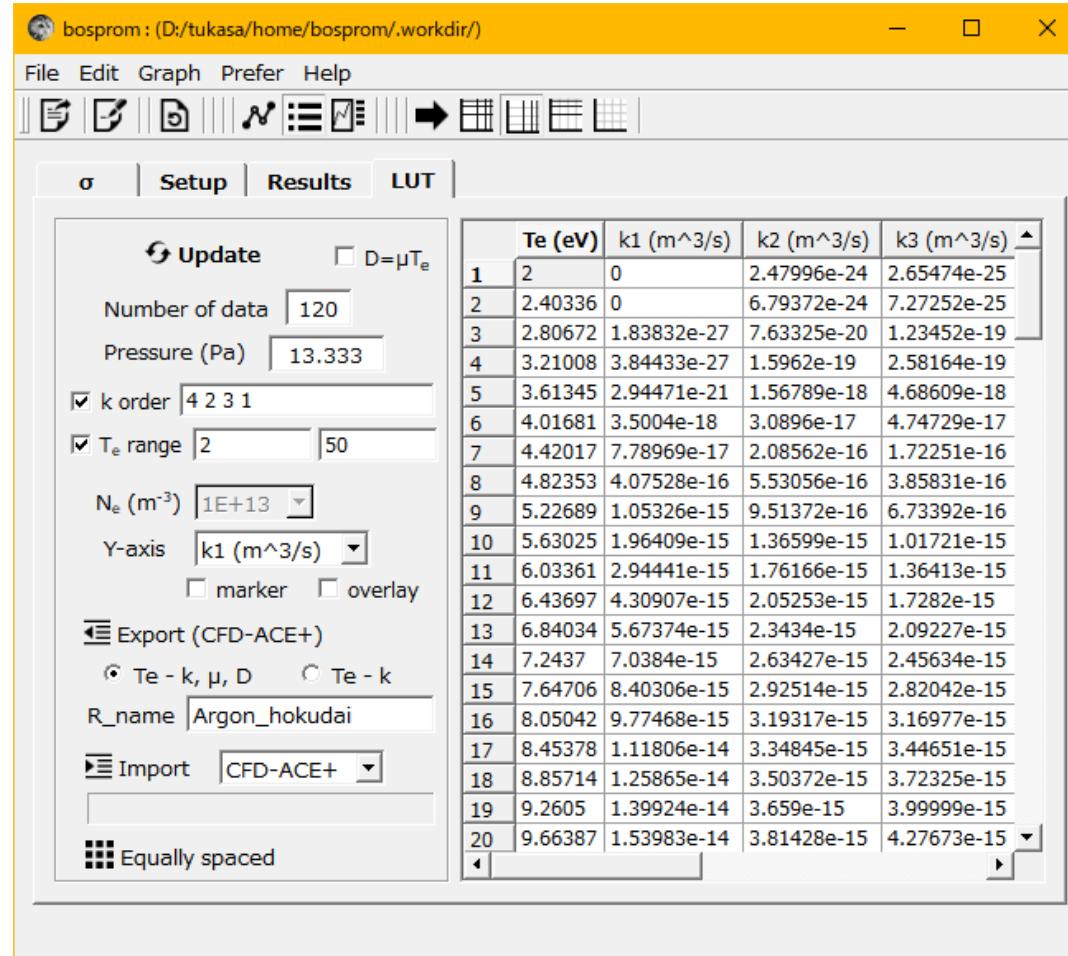


Bosprom:結果表示画面





Bosprom: プラズマ計算用 lookup-table 作成画面



- 計算結果から T_e ベースの LUT (lookup-table) を作成
- CFD-ACE+ や BOLSIG+ のファイルを import してグラフ表示・編集も可能



Lennard-Jones パラメータ推算ツール



分子の加算因子・沸点から Lennard-Jones パラメータを推算

熱流体・プラズマのシミュレーションで必要となる species data を準備

表 2 - 1

Lyndersen の臨界定数の加算因子

| | 個数 | | 個数 |
|----------|----|-----------------|----|
| 非環状加算因子 | | ハロゲン加算因子 | |
| -CH3 | 1 | -F | 5 |
| -CH2- | 0 | -Cl | 0 |
| >CH- | 0 | -Br | 0 |
| >C< | 0 | -I | 0 |
| =CH2 | 0 | 酸素加算因子 | |
| =CH- | 0 | -OH(Alcohol) | 0 |
| =C< | 0 | -OH(Phenol) | 0 |
| =C= | 0 | -O- | 0 |
| #CH | 0 | -O-(R) | 0 |
| #C- | 0 | >C=O | 0 |
| 環状加算因子 | | >C=O(R) | 0 |
| -CH2-(R) | 0 | O=HC-(Aldehyde) | 0 |
| >CH-(R) | 0 | -COOH(Acid) | 0 |
| >C<(R) | 0 | -COO-(Ester) | 0 |
| =CH-(R) | 6 | =O | 0 |
| =C<(R) | 0 | | |
| =C=(R) | 0 | | |

| | 個数 |
|---------|----|
| 窒素加算因子 | |
| -NH2 | 0 |
| >NH | 0 |
| >NH(R) | 0 |
| >N- | 0 |
| >N-(R) | 0 |
| -CN | 0 |
| -NO2 | 0 |
| イオウ加算因子 | |
| -SH | 0 |
| -S- | 0 |
| -S-(R) | 0 |
| =S | 0 |
| その他 | 0 |
| >Si< | 0 |
| >B- | 0 |

| Lyndersen の方法 | |
|---------------|----------------|
| 標準沸点 Tb(K) : | 390.65 (Input) |
| 分子量 (M) : | 182.10 (Input) |
| 偏心因子 ω | 0.51 |
| Tc | 548.65 |
| Pc | 26.71 |
| Vc | 401.00 |
| Lennard-Jones | |
| σ | 6.33 |
| ϵ/k | 481.79 (K) |



電子衝突断面積の推算ツール

QEC

反応モデルのデータベース

QDB



Quantemol Ltd was founded in 2004 as a spin-out of University College London's Physics Department. We develop software tools based on highly sophisticated research codes and provide unique data for plasma modelling

We can offer as consultancy:



- ✓ Elastic collisions and momentum transfer
- ✓ Electron and rotational excitation
- ✓ Super-elastic cross-sections
- ✓ Quenching cross-sections
- ✓ Dissociative electron attachment
- ✓ Electron impact ionisation

... and more!

- Electron collision cross-section calculations
- Calculations for new type of molecules (such as precursors for deposition)
- Photoionization calculations
- Cross-sections for molecules containing heavy atoms (Ti, In, I, Ga ...)
- Electron impact dissociation
- Electron impact ionisation

... and more!



- ✓ > 40 pre-assembled self-consistent chemistry sets
- ✓ Download formats for plasma modelling software: QVT, CHEMKIN, Comsol, **CFD-ACE+**, VizGlow...
- ✓ Dynamic Chemistry for fast chemistry assembling
- ✓ Data comparison between individual reactions
- ✓ User-friendly interface

- Assemble a chemistry set for your gas mixture
- Optimise it for your pressure conditions reducing from hundreds to dozens of reactions without loosing key reactions
- Estimate or calculate missing reactions
- Create a surface chemistry mechanisms set & calibrate it with your experiment
- Run multiple calculations & conduct a sensitivity analysis for explored contributing factors

Based in London, we work with academic and industrial partners around the globe, including customers in:





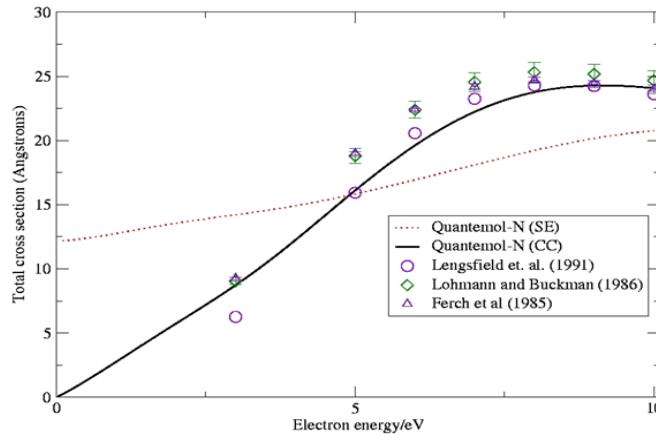
Cross sections validation by QEC

Input: ONLY geometry!

Output: cross sections, Reaction rates

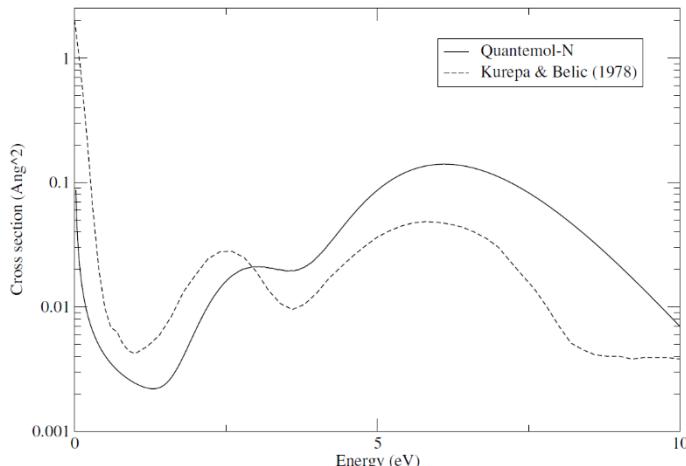


Total cross sections for e-CH₄



“Methane/hydrogen plasmas have been reported to be sources both for a-C:H film deposition and for compound semiconductor etching.” – Duan 2011

Dissociative attachment to Cl₂



“Atomic chlorine and its ions are a very common in silicon etching... and thus data regarding the chlorine molecule’s dissociation are needed. The chlorine gas is highly toxic and therefore measurements of this substance are dangerous” – Hamilton 2017



Dynamic Chemistry App

Feed gases

- Choose your chemistry among the species available in QDB

Species

- The app will scan the database and find all possible species related to your chemistry. Choose the ones you want to be included in your set

Reactions

- The app will search for all reactions with the species you chose. You can select ones you want to include

Gold users: Download data in formats compatible with: HPEM, **CFD-ACE+** (CHEMKIN), COMSOL, VisGlow





Set Generation

※ Dynamic Chemistry App の例

QDB Global Model

Set Generation Chemistry Set Model Settings Results

Dynamic Set Generation

Gas Selection

| | |
|---|--|
| <input type="checkbox"/> Ar | <input type="checkbox"/> N2 |
| <input type="checkbox"/> H2 | <input type="checkbox"/> O2 |
| <input type="checkbox"/> Al | <input type="checkbox"/> HBr |
| <input type="checkbox"/> He | <input checked="" type="checkbox"/> SiH4 |
| <input type="checkbox"/> CH4 | <input type="checkbox"/> CF4 |
| <input checked="" type="checkbox"/> NH3 | <input type="checkbox"/> F2 |
| <input type="checkbox"/> Ne | <input type="checkbox"/> Kr |
| <input type="checkbox"/> Xe | <input type="checkbox"/> CO2 |
| <input type="checkbox"/> Cl2 | <input type="checkbox"/> SO2 |
| <input type="checkbox"/> C2H2 | <input type="checkbox"/> BCl3 |
| <input type="checkbox"/> SiCl4 | <input type="checkbox"/> SiF4 |
| <input type="checkbox"/> Cu | <input type="checkbox"/> CO |
| <input type="checkbox"/> HF | <input type="checkbox"/> NF3 |
| <input type="checkbox"/> CHF3 | <input type="checkbox"/> C4F8 |
| <input type="checkbox"/> SF6 | <input type="checkbox"/> CH3F |
| <input type="checkbox"/> C4F6 | |

Add to Selection Generate Set

Pre-Assembled Sets Load Set

NH₃ と SiH₄ を選択した例

The screenshot shows the 'Set Generation' tab of the QDB Global Model interface. In the 'Gas Selection' section, two gases are selected: NH₃ and SiH₄. Other gases listed include Ar, H₂, Al, He, CH₄, N₂, O₂, HBr, CF₄, F₂, Kr, CO₂, SO₂, BCl₃, SiF₄, CO, NF₃, C₄F₈, and CH₃F. Below the selection list are buttons for 'Add to Selection' and 'Generate Set'. At the bottom, there is a section for 'Pre-Assembled Sets' with a 'Load Set' button.



Chemistry Set

Species と reaction steps の確認

QDB Global Model

Set Generation Chemistry Set Model Settings Results

| | Name | Sticking Coefficient | Return Coefficient | Return Species |
|-------------------------------------|--------------------|----------------------|--------------------|----------------|
| <input checked="" type="checkbox"/> | Properties H | 0.0000 | 0.0000 | H |
| <input checked="" type="checkbox"/> | Properties H+ | 1.0000 | 1.0000 | H |
| <input checked="" type="checkbox"/> | Properties H- | 1.0000 | 1.0000 | H |
| <input checked="" type="checkbox"/> | Properties H2 | 0.0000 | 0.0000 | H2 |
| <input checked="" type="checkbox"/> | Properties H2+ | 1.0000 | 1.0000 | H2 |
| <input checked="" type="checkbox"/> | Properties H2[*] | 1.0000 | 1.0000 | H2 |
| <input checked="" type="checkbox"/> | Properties H2[v=+] | 1.0000 | 1.0000 | H2 |
| <input checked="" type="checkbox"/> | Properties H3+ | 0.0000 | 0.0000 | H3+ |
| <input checked="" type="checkbox"/> | Properties H[n=2] | 1.0000 | 1.0000 | H |
| <input checked="" type="checkbox"/> | Properties H[n=3] | 1.0000 | 1.0000 | H |
| <input checked="" type="checkbox"/> | Properties H[n=4] | 1.0000 | 1.0000 | H |
| <input checked="" type="checkbox"/> | Properties H[n=5] | 1.0000 | 1.0000 | H |

Auto-Add Reactions Add Species

Filtering

Show only selected species

Ground State Neutrals

Excited States

Positive Ions

Negative Ions

Excited States

Use pooled states

Use distinct states

Enable Consistency Checks

Some Ion-Ion Recombination reactions are missing!

The following species are not consumed by any gas phase reactions:

M : No loss channels in gas phase or at surfaces Si2H4 : No loss channels in gas phase or at surfaces Si3H7 : No loss channels in gas phase or at surfaces Si4H9 : No loss channels in gas phase or at surfaces
 Si6H13 : No loss channels in gas phase or at surfaces Si7H15 : No loss channels in gas phase or at surfaces Si8H17 : No loss channels in gas phase or at surfaces Si9H20 : No loss channels in gas phase or at surfaces Si5H11 : No loss channels in gas phase or at surfaces
 Si2H2+ : No loss channels in gas phase or at surfaces Si2H5+ : Consumed only at surfaces Si2H6+ : Consumed only at surfaces N+2 : Consumed only at surfaces

Reaction

| | A | n | E | |
|--|---------------------------|----------|-------|-------|
| <input checked="" type="checkbox"/> Info | e- + H2 > e- + H + H | 1.15e-07 | -0.58 | 11.56 |
| <input checked="" type="checkbox"/> Info | e- + H2 > e- + H + H | 1.00e-08 | 0.24 | 12.06 |
| <input checked="" type="checkbox"/> Info | e- + H2 > e- + e- + H2+ | 1.09e-08 | 0.46 | 16.03 |
| <input checked="" type="checkbox"/> Info | e- + H2 > e- + H + H[n=2] | 1.96e-10 | 0.27 | 14.99 |
| <input checked="" type="checkbox"/> Info | e- + H2+ > e- + H2+ | 1.44e-04 | -1.19 | 0.05 |
| <input checked="" type="checkbox"/> Info | e- + H2+ > e- + H + H | 2.72e-07 | -0.24 | 2.74 |
| <input checked="" type="checkbox"/> Info | e- + H2+ > H + H | 4.94e-08 | -0.50 | 0.03 |
| <input checked="" type="checkbox"/> Info | e- + H > e- + H | 1.97e-07 | -0.29 | 0.22 |
| <input checked="" type="checkbox"/> Info | e- + H > e- + e- + H | 4.54e-09 | 0.72 | 13.55 |

Auto-Update Species Add Reaction

Filter by Type Filter by Reactants Filter by Products

Has Reactants

show electron collisions

show heavy particle collisions

Has Products



Model Settings

装置の寸法やプロセス条件の設定

QDB Global Model

- □

Set Generation Chemistry Set Model Settings Results

Operating Parameters

Pressure: 160.00 Pascal

Power: 10.00 Watt

Gas Temperature: 600.00 K

Pulse Power

Geometry

Height: 0.030000 m

Radius: 0.075000 m

Flows

H₂: 0.00 sccm

N₂: 0.00 sccm

NH₃: 45.00 sccm

SiH₄: 1.80 sccm

Parameter Variation

Please enter a name for the run: 160Pa_10W_600K_H0p03_R0p075_NH3_45_SiH4_1p8

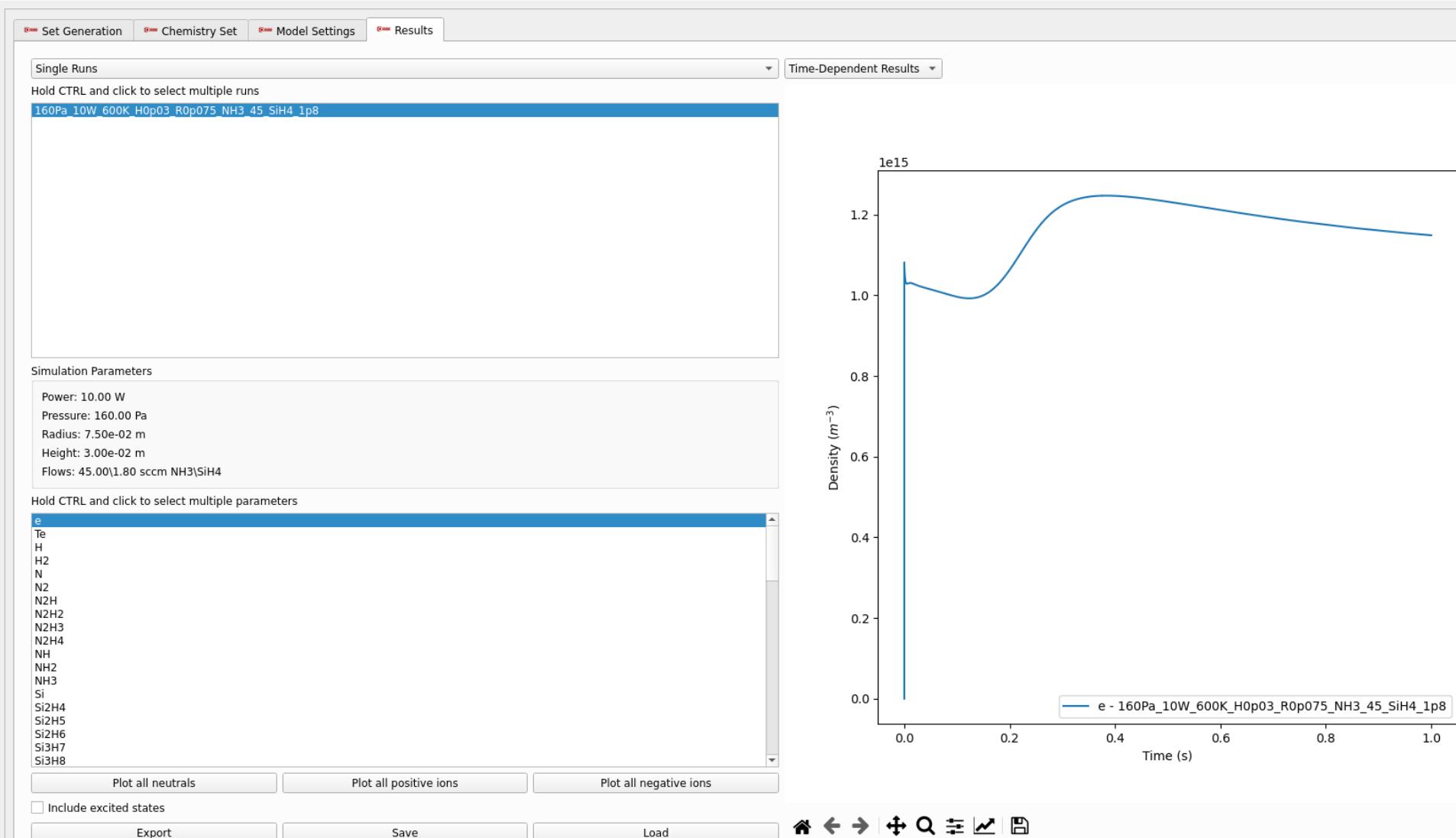
Run



Results

計算終了後の結果

QDB Global Model





Results (Final neutral species) 中性粒子の数密度の結果

